



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS RECEIVES MTX ORDER FROM
A LEADING MEMORY MODULE MANUFACTURER**

Fremont, CA (March 27, 2007) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has expanded the customer base for its MTX model Fp+ test during burn-in system following the receipt of an order from a leading memory module manufacturer. The system will ship during the next three months and will be used to test and burn-in high-reliability memory modules.

“We are very excited about this order,” said Greg Perkins, vice president of worldwide sales and service of Aehr Test Systems. “We will be working closely with this customer to utilize the capabilities of our MTX-Fp+ for what we see as a logical extension of the traditional burn-in and test of individual memory devices that our customers have done for years on our MTX systems. By burning-in the assembled modules, this supplier should be able to provide ultra high reliability modules for their customers that need a higher level of reliability than normal for critical applications. We are very pleased to establish this new relationship that we believe could lead to additional follow-on orders in the future.”

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOXTM, MTX and MAX systems and the DiePak[®] carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test’s products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the MTX technology, acceptance by customers of the MTX systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs

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or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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